

# **2007 IEEE Autotestcon**

**Baltimore, MD  
17-20 September 2007**

**Volume 1 of 2**



<b>IEEE Catalog Number:</b>	<b>CFP07AUT-PRT</b>
<b>ISBN 10:</b>	<b>1-4244-1238-2</b>
<b>ISBN 13:</b>	<b>978-1-4244-1238-9</b>

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